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(54) Title: A TESTING HEAD WITH AN IMPROVED CONTACT BETWEEN CONTACT PROBES AND GUIDE HOLES

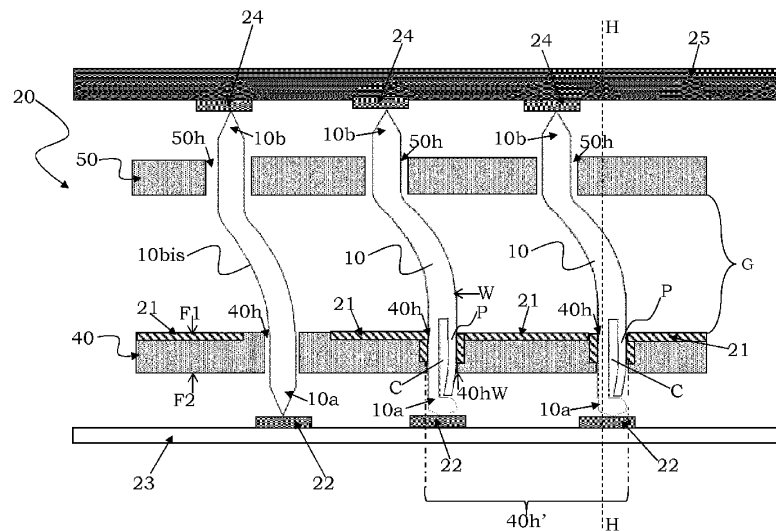


FIG. 1

(57) Abstract: A testing head (20) for testing the functionality of an electronic device comprises a plurality of contact probes (10, 10bis) including a probe body (10') longitudinally extended between respective end portions (10a, 10b) which are adapted to contact respective contact pads, at least one lower guide (40) provided with guide holes (40h) for slidably housing the contact probes (10, 10bis), and a conductive portion (21) in the lower guide (40), this conductive portion (21) including at least one group (40h') of the guide holes (40h) and being adapted to contact and short-circuit a corresponding group of contact probes (10) housed in this group (40h') of holes and intended to carry a certain type of signal. Suitably, at least the contact probes (10) housed in this group (40h') of holes comprise an elastically deformable portion (P) which is adapted to be at least partially inserted into the guide holes of this group (40h'), wherein this portion (P), when housed in the guide holes of this group (40h'), is in a configuration in which it is deformed by

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the contact with at least one wall (40hW) of these guide holes and it exerts on this wall (40hW) a reaction force (F) ensuring a sliding contact during the test of the electronic device.